

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Nishimura et al.

Application No. 10/816,467

Filed: March 31, 2004

Confirmation No. 8404

For: CHARGED-PARTICLE-BEAM MAPPING
PROJECTION-OPTICAL SYSTEMS AND
METHODS FOR ADJUSTING SAME

Examiner: not yet assigned

Art Unit: 2881

Attorney Reference No. 4641-68043-01

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Attorney
for Applicant(s)

Donald L. Styling

Date Mailed August 13, 2004

**INFORMATION DISCLOSURE STATEMENT
FOR CONTINUING APPLICATIONS**

Listed on the accompanying form PTO-1449 are several English-language documents.

Applicants respectfully request that such documents be listed as references cited on the issued patent.

The present application relies upon U.S. Patent Application No. 09/302,075, which was filed April 28, 1999, for an earlier filing date under 35 U.S.C. § 120. Furthermore, several documents listed on the accompanying form PTO-1449 were disclosed to or cited by the Patent Office in the earlier U.S. application.

Copies of the documents listed on the accompanying form PTO-1449 that were cited by applicants in the earlier application need not be sent to the Patent Office pursuant to 37 C.F.R. § 1.98. However, applicants will furnish the Patent Office with such copies upon request.

Since the present application was filed after June 30, 2003, copies of United States patents and United States published patent applications do not have to be provided to the Patent Office. This requirement of 37 C.F.R. § 1.98(a)(2)(i) has been waived by the United States Patent and Trademark Office pursuant to the Official Gazette Notice on August 5, 2003 (1276 OG 55). Applicants will provide copies of such patents upon request.

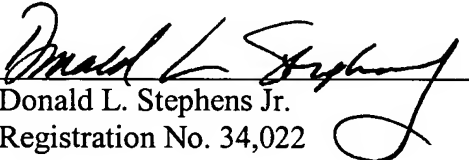
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The filing of this Information Disclosure Statement shall not be construed to be an admission that the information cited in the statement is, or is considered to be, prior art or otherwise material to patentability as defined in 37 C.F.R. §1.56.

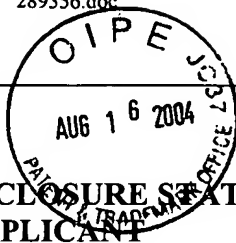
Respectfully submitted,

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Attorney Docket Number	4641-68043-01
	Application Number	10/816,467
	Filing Date	March 31, 2004
	First Named Inventor	Nishimura
	Art Unit	2881
	Examiner Name	not yet assigned

U.S. PATENT DOCUMENTS

NOTE: If this application was filed after June 30, 2003, copies of United States patents and United States published patent applications do not have to be provided to the Patent Office. This requirement of 37 C.F.R. § 1.98(a)(2)(i) has been waived by the United States Patent and Trademark Office pursuant to the Official Gazette Notice on August 5, 2003 (1276 OG 55).

Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee
		6,107,636	22-Aug-2000	Muraki
		6,365,897	2-Apr-2002	Hamashima et al.
		6,593,152	15-Jul-2003	Nakasuji et al.
		6,608,308	19-Aug-2003	Takagi et al.
		6,653,631	25-Nov-2003	Nishimura
		6,661,008	9-Dec-2003	Takagi et al.
		6,717,145	6-Apr-2004	Takagi et al.
		2002/0033449	21-Mar-2002	Nakasuji et al.
		2003/0207475	6-Nov-2003	Nakasuji et al.

Examiner's Initials*	Cite No. (optional)	OTHER DOCUMENTS
		Tsuno, "Simulation of a Wien Filter as Beam Separator in a Low Energy Electron Microscope," <i>Ultramicroscopy</i> 55:127-140 (1994).

EXAMINER SIGNATURE:	DATE CONSIDERED:
<p>* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	